REMARKS

This Request for Continued Examination (RCE) Application is being filed in an abundance of caution to permit consideration of a Supplemental Information Disclosure Statement.

No new matter is being presented in this application.

A telephonic interview is requested in the event that the next office action is one other than a Notice of Allowance. The undersigned is available during normal business hours (Pacific Time Zone).

Respectfully submitted,

Dated: 08 Nov 2004

By:

Reg. No. 44,854

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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

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Application Serial No	9,335
*Confirmation No	4063
Filing Date June 11,	2001
Inventor Vishnu K. Agarwal,	, et al
Assignee Micron Technology	, Inc.
Group Art Unit	2813
Examiner	ıpson
Attorney's Docket No	·1568
Customer No	1567
Title: Conseiter Forming Matheda and Conseiter Constructions	

Title: Capacitor Forming Methods and Capacitor Constructions

INFORMATION DISCLOSURE STATEMENT

References -- See Attached Form PTO-1449

REMARKS

The citation listed may be material to the examination of the subject application and are therefore submitted in compliance with the duty of disclosure defined in 37 CFR §1.56. The Examiner is requested to make this citation of official record in this application. No admission is made regarding whether the submitted reference is prior art.

Respectfully submitted,

Dated: 08 Nov 2004

\ttorney:____

Lake

Reg. No.: 44,854

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1568			SERIAL NO. 09/879,335				
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U.S. PATENT DOCUMENTS											
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.											